

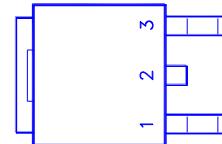
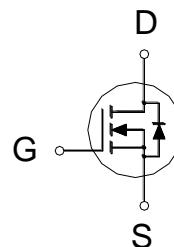
**NIKO-SEM****N-Channel Enhancement Mode  
Field Effect Transistor****P1006BD**

TO-252

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
60V	10mΩ	66A



1: GATE  
2: DRAIN  
3: SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	60	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>2</sup>	$T_C = 25^\circ C$	$I_D$	66	A
	$T_C = 100^\circ C$		42	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	150	A
Avalanche Current		$I_{AS}$	38.5	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	74	mJ
Power Dissipation	$T_C = 25^\circ C$	$P_D$	96	W
	$T_C = 100^\circ C$		38	
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C/W
Junction-to-Case	$R_{\theta JC}$		1.3	

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Package limitation current is 30A**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ C$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.3	1.8	2.3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48V, V_{GS} = 0V$			1	$\mu A$
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ C$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 20A$		8.1	13	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$		6.8	10	

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Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 20A$	60		S
<b>DYNAMIC</b>					
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	1920		pF
Output Capacitance	$C_{oss}$		215		
Reverse Transfer Capacitance	$C_{rss}$		140		
Gate Resistance	$R_g$		0.7		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_{g(VGS=10V)}$	$V_{DS} = 30V, I_D = 20A$	42		nC
	$Q_{g(VGS=4.5V)}$		23		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		6		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		12		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DS} = 30V, I_D \geq 20A,$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	29		nS
Rise Time <sup>2</sup>	$t_r$		31		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		51		
Fall Time <sup>2</sup>	$t_f$		31		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>					
Continuous Current <sup>3</sup>	$I_S$			66	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 20A, V_{GS} = 0V$		1.3	V
Diode Reverse Recovery Time	$t_{rr}$	$I_F = 20A, dI/dt = 100A/\mu s$	26		nS
Diode Reverse Recovery Charge	$Q_{rr}$		19		nC

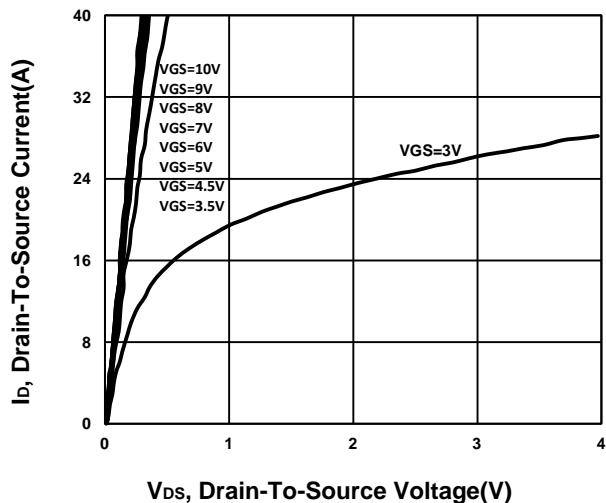
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Package limitation current is 30A

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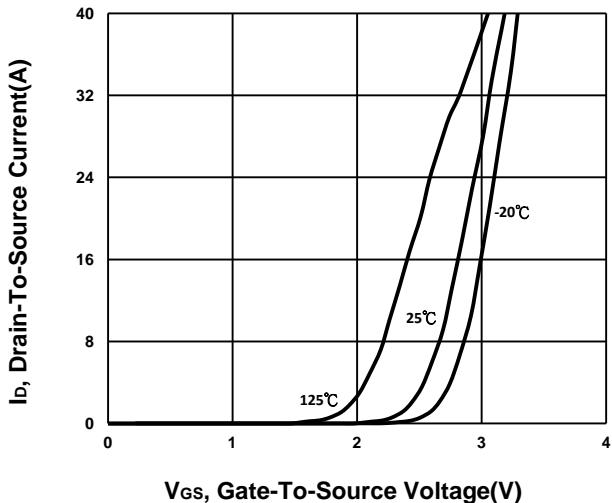
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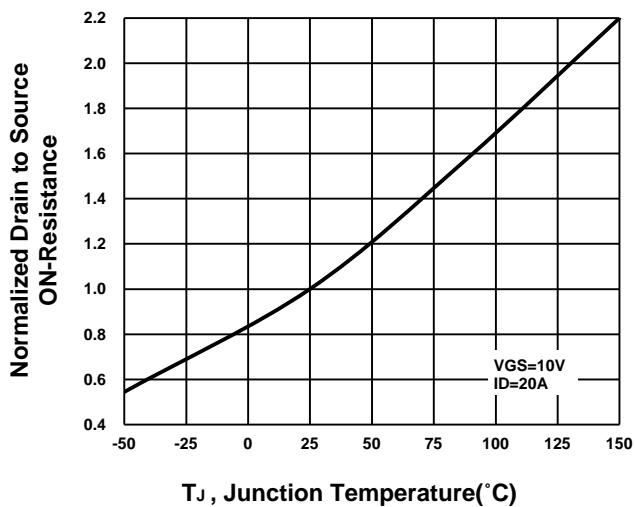
### Output Characteristics



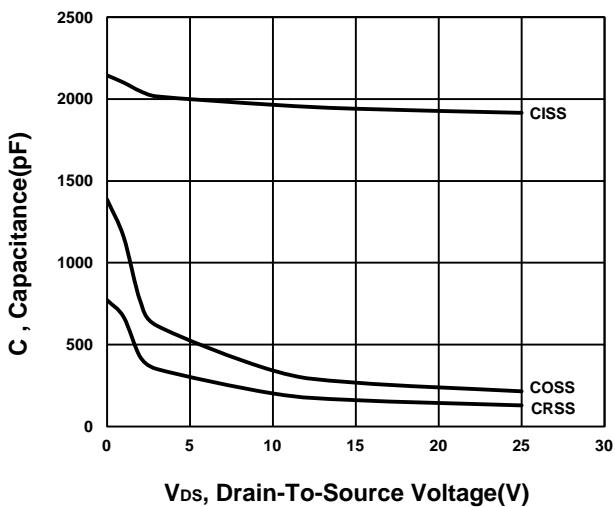
### Transfer Characteristics



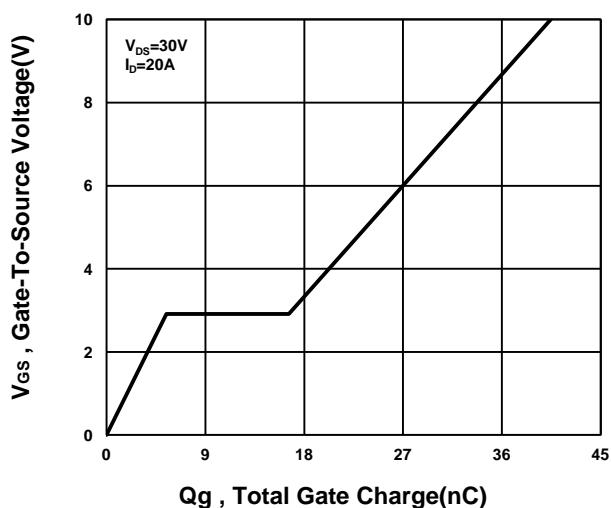
### On-Resistance VS Temperature



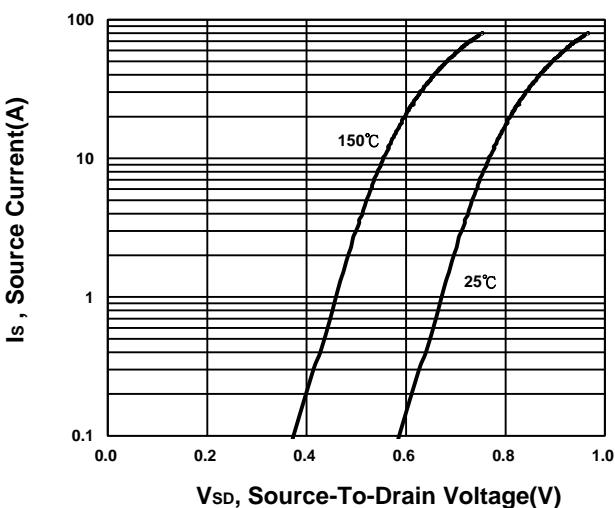
### Capacitance Characteristic



### Gate charge Characteristics



### Source-Drain Diode Forward Voltage

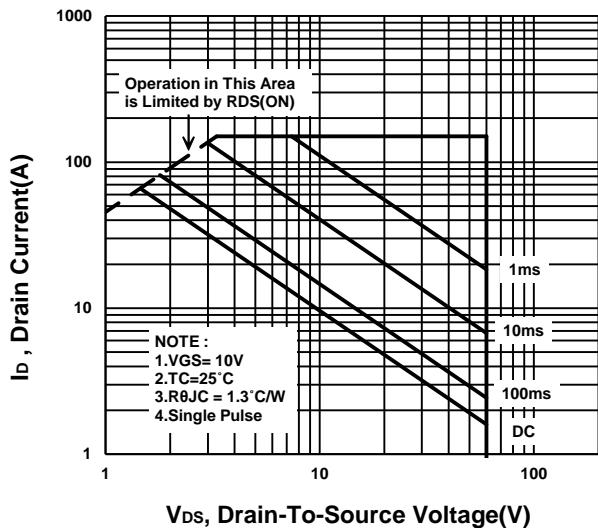


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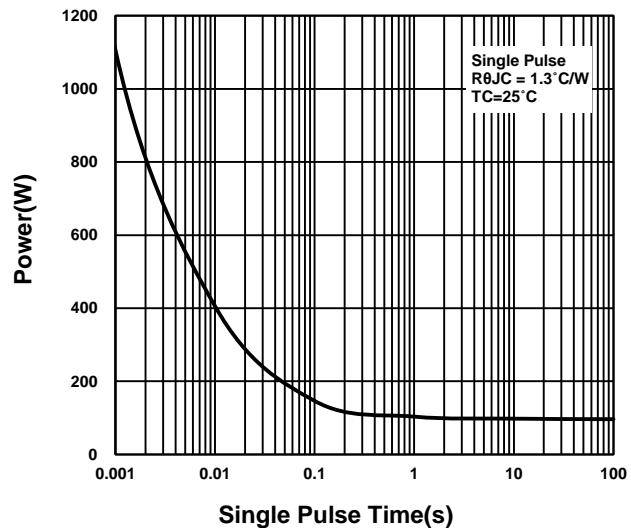
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### Safe Operating Area



### Single Pulse Maximum Power Dissipation



### Transient Thermal Response Curve

